Application/Control No. Applicant(s)/Patent Under Reexamination BARBEE ET AL. Examiner Katarzyna W. Lee Applicant(s)/Patent Under Reexamination BARBEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,384,121 B1	05-2002	Barbee et al.	524/445
	В	US-6,124,365	09-2000	Lan et al.	516/101
	, C	US-6,232,388 B1	05-2001	Lan et al.	524/445
	D	US-6,057,396	05-2000	Lan et al.	524/445
	E	US-6,162,857	12-2000	Trexler, Jr. et al.	524/445
	F	US-6,084,019	07-2000	Matabayas, Jr. et al.	524/445
	G	US-6,407,155 B1	06-2002	Qian et al.	524/445
	Н	US-6,262,162	07-2001	Lan et al.	524/445
	1	US-6,242,500 B1	06-2001	Lan et al.	516/101
	J	US-6,225,394 B1	05-2001	Lan et al.	524/445
	К	US-6,387,996 B1	05-2002	Lan et al.	524/445
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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